

Docket No.: SON-2810
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Yoshitaka Kayukawa, et al.

Application No.: Not Yet Assigned

Filed: August 26, 2003

Art Unit: N/A

For: SEMICONDUCTOR INTEGRATED CIRCUIT
AND METHOD FOR TESTING SAME

Examiner: Not Yet Assigned

PRELIMINARY AMENDMENT ACCOMPANYING FILING

MS Patent Application
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Prior to the initial examination, please amend the above-identified application as follows:

IN THE SPECIFICATION:

Please amend the specification as shown below.

Please replace the paragraph beginning on page 8, line 5, with the following rewritten paragraph:

Fig. 2, consisting of Figs. 2A, 2B, 2C, 2D and 2E, is a wave form chart illustrating the resetting operation of a scan chain on an embodiment of the present invention;

Please replace the paragraph beginning on page 8, line 7, with the following rewritten paragraph:

Fig. 3, consisting of Figs. 3A, 3B, 3C, 3D, and 3E, is a wave form chart illustrating the motion for the creation of a scan pattern on an embodiment of the present invention; and